

| Search Terms | |
|--------------|--|
| 1 | ABCD |
| 2 | ABCDs |
| 3 | DE-EMBED |
| 4 | DE-EMBEDDED |
| 5 | DE-EMBEDDEDs |
| 6 | DE-EMBEDDING |
| 7 | DE-EMBEDDINGS |
| 8 | DE-EMBEDS |
| 9 | ((DE-EMBED OR DE-EMBEDDED OR DE-EMBEDDING) AND ABCD) |

| | Total | US-PGPUB | USPAT | USOCR | EPO | JPO | Derwent | IBM TDB |
|---|-------|----------|-------|-------|-----|-----|---------|---------|
| 1 | 8992 | | | | | | | |
| 2 | 3 | | | | | | | |
| 3 | 36 | | | | | | | |
| 4 | 81 | | | | | | | |
| 5 | 0 | | | | | | | |
| 6 | 143 | | | | | | | |
| 7 | 0 | | | | | | | |
| 8 | 4 | | | | | | | |
| 9 | 6 | | | | | | | |

| | U | 1 | Document ID | Issue Date | Pages | Title | Current OR |
|---|---|---|-------------------|------------|-------|---|------------|
| 1 | X | | US 20050027469 A1 | 20050203 | 12 | De-embedding devices under test | 702/117 |
| 2 | X | | US 20040031001 A1 | 20040212 | | MOSFET modeling for IC design accurate for high frequencies | 716/4 |
| 3 | X | | US 20030132759 A1 | 20030717 | 12 | Low loss integration of wafer probes with microwave tuners | 324/601 |
| 4 | X | | US 20020024593 A1 | 20020228 | | 3D scanning using shadows | 348/46 |
| 5 | X | | US 6851097 B2 | 20050201 | | MOSFET modeling for IC design accurate for high frequencies | 716/5 |
| 6 | X | | US 6618837 B1 | 20030909 | | MOSFET modeling for IC design accurate for high frequencies | 716/4 |

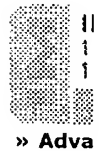
| | Current XRef | Retrieval Classif | Inventor | S | C | P | 2 | 3 | 4 | 5 | Image Doc. Displayed | PT |
|---|--|-------------------|---------------------------|---|---|---|---|---|---|---|-------------------------|----|
| 1 | | | Brunsmann, Michael D. | | | | | | | | US 20050027469 | |
| 2 | 703/14 | | Zhang, Xisheng et al. | | | | | | | | | |
| 3 | | | Tsironis, Christos | | | | | | | | US 20030132759 | |
| 4 | 382/154 | | Bouquet, Jean-Yves et al. | | | | | | | | | |
| 5 | 703/14; 703/2; 716/1; 716/4; 716/6 | | Zhang, Xisheng et al. | | | | | | | | | |
| 6 | 703/14; 716/1 | | Zhang, Xisheng et al. | | | | | | | | | |

| Search Terms | |
|--------------|----------------------|
| 1 | BRUNSMAN-MICHAEL |
| 2 | BRUNSMAN-MICHAELS |
| 3 | BRUNSMAN-MICHAEL.IN. |

| | Total | US-PGPUB | USPAT | USOCR | EPO | JPO | Derwent | IBM TDB |
|---|-------|----------|-------|-------|-----|-----|---------|---------|
| 1 | 0 | | | | | | | |
| 2 | 0 | | | | | | | |
| 3 | 0 | | | | | | | |

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Example: optical <and> (fiber <or> fibre) <in> ti
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 (de-embedding<or>de-embedded)
 <and>ABCD

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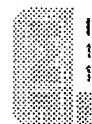
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